San Francisco | February 24 – 28 | Moscone Center



SESSION ID: CRYP-T12

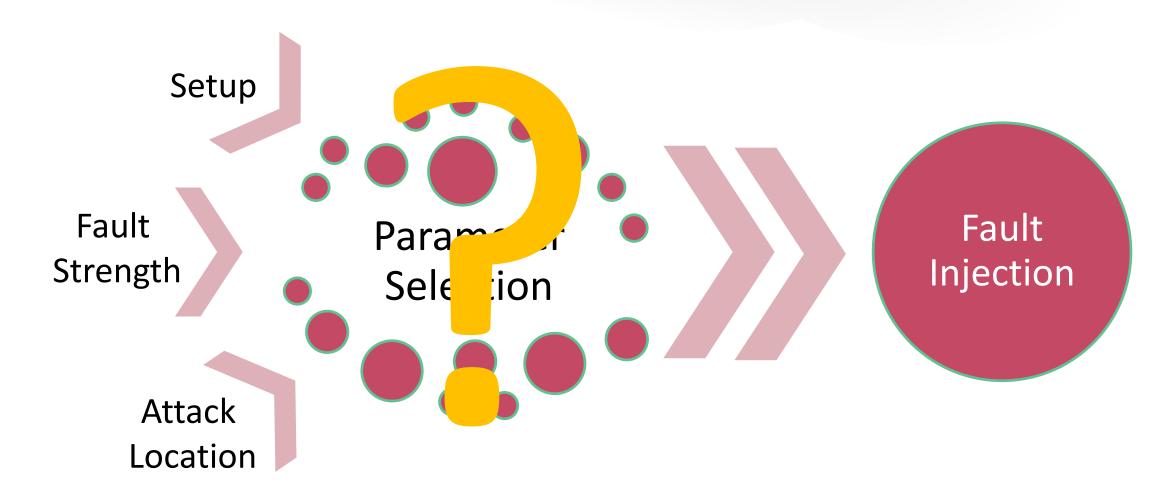
A Fast Characterization Method for Semi-invasive Fault Injection Attacks



Stjepan Picek

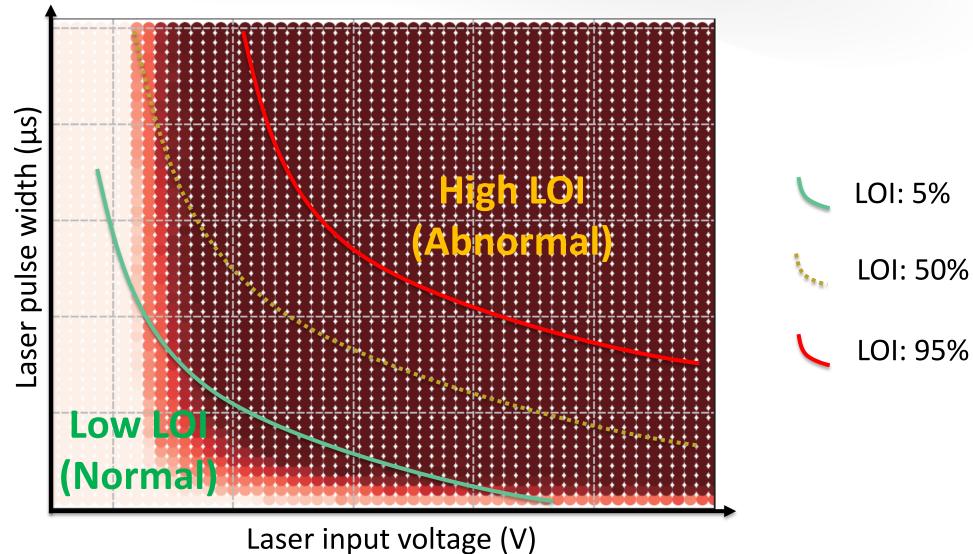
Assistant professor TU Delft, The Netherlands

Why Characterization?





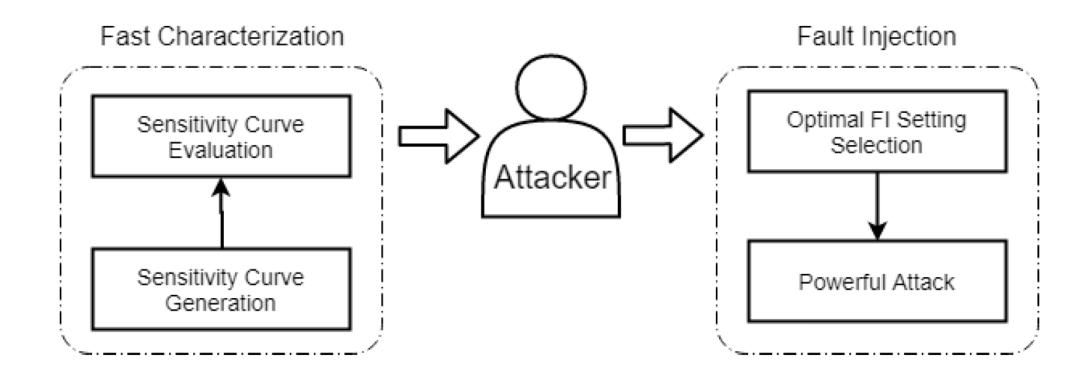
How to Characterize?





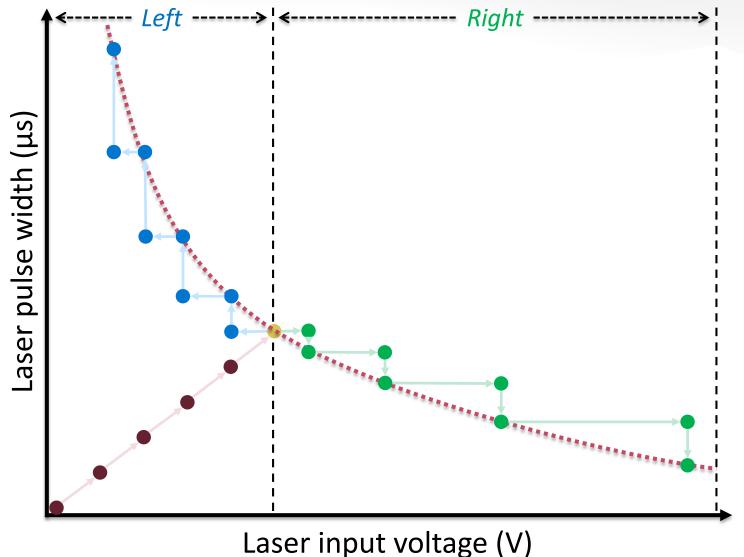
Fast Characterization Methodology

Attack Workflow





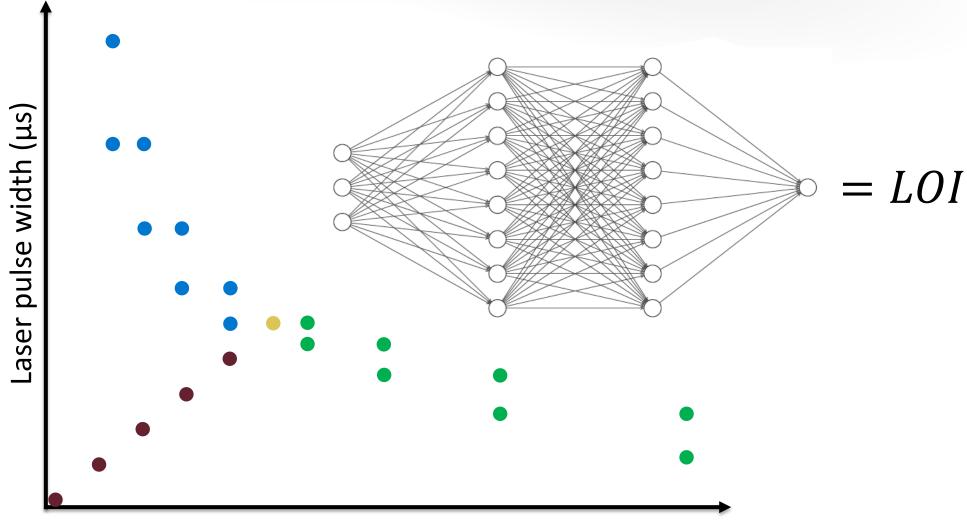
Sensitivity Curve Generation



- Sensitivity curve
- Diagonal search
- Golden point
- Left search
- Right search

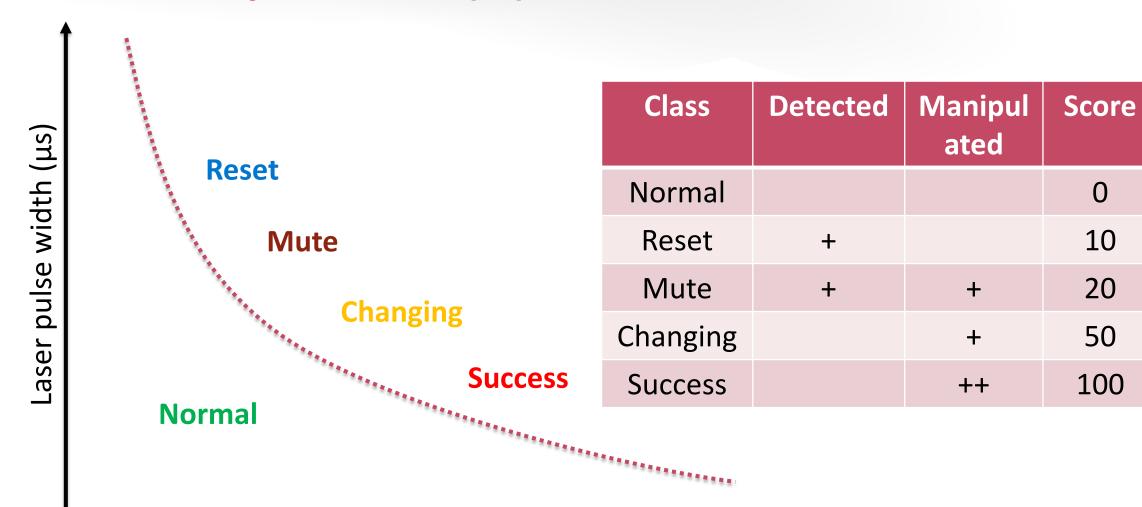


Evaluation: Predicting LOIs





Evaluation: Impact Score (IS)



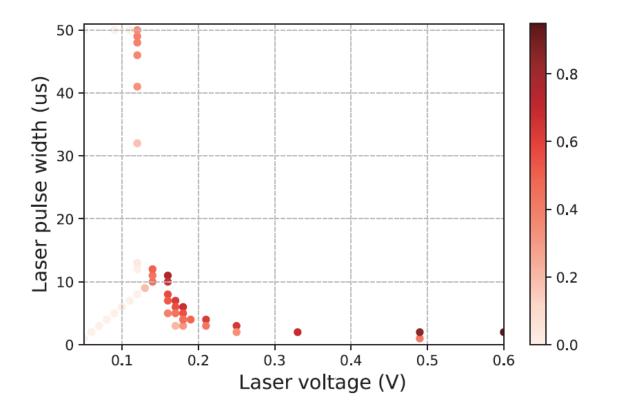




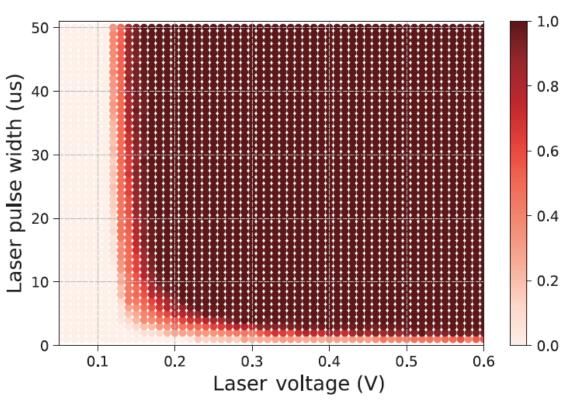
Experimental Results

Sensitivity Curve Generation

Sensitivity Curve



Exhaustive Scan

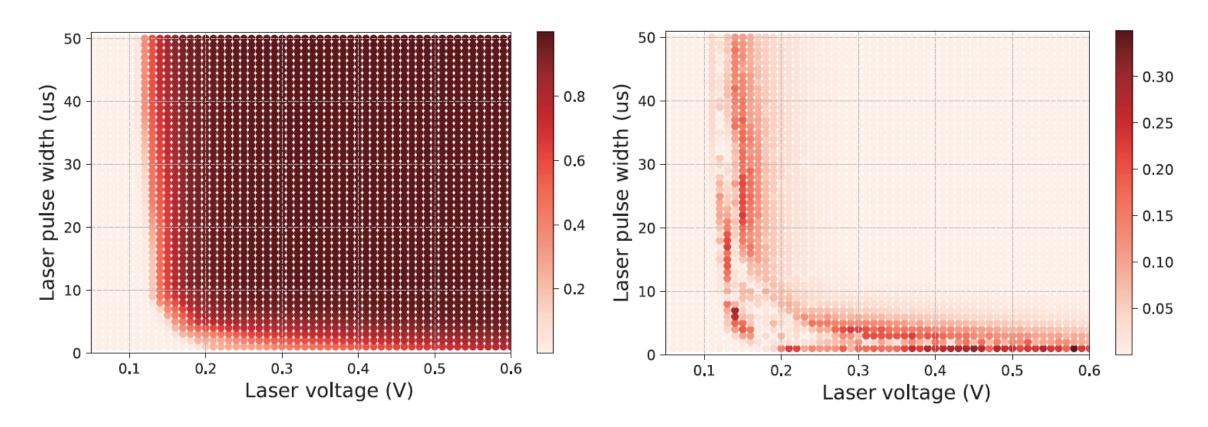




Sensitivity Curve Evaluation: Predicting LOIs

Prediction Result

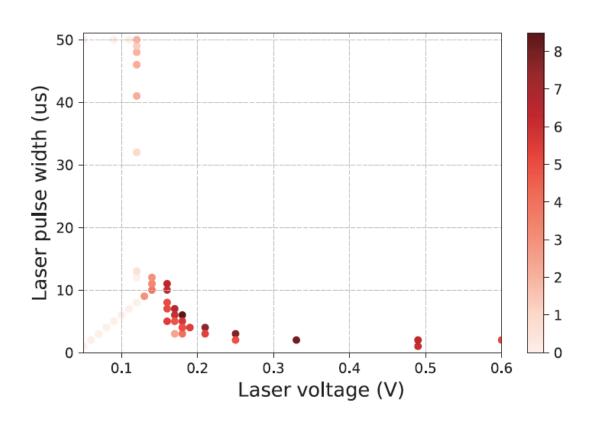
Exhaustive Scan/Prediction Error



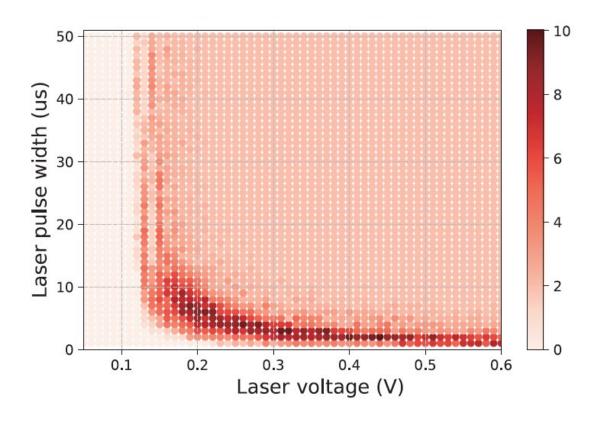


Sensitivity Curve Evaluation: Impact Score (IS)

Sensitivity Curve



Exhaustive Scan





Apply It!

A stable and effective method for real evaluation

Back to Origin





Attack Strategically

Sensitivity Curve Evaluation

Sensitivity Curve Generation



Optimal Parameter Selection





Thank you!

Questions?